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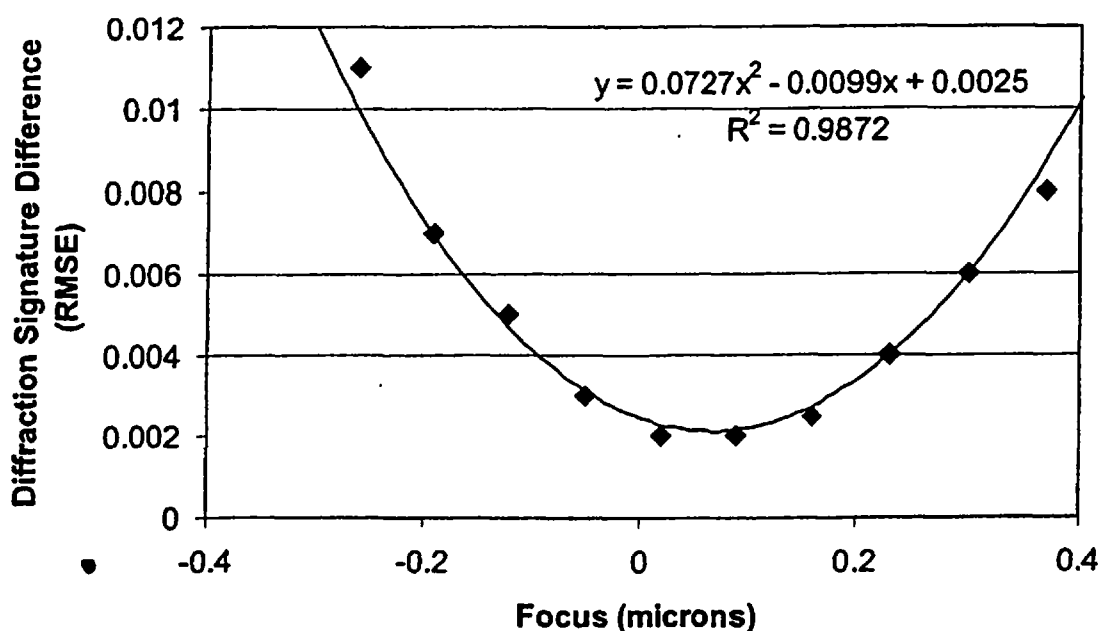
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(54) Title: DETERMINATION OF CENTER OF FOCUS BY DIFFRACTION SIGNATURE ANALYSIS



(57) Abstract: The present invention provides methods for determination in lithographic wafer (10) by diffraction signature difference analysis utilizing a plurality of diffraction gratings (20).



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WO 02/21075 A1